TOSHIBA Photocoupler GaAlAs Ired & Photo IC

# TLP2530, TLP2531

**Digital Logic Isolation** 

Line Receiver

**Power Supply Control** 

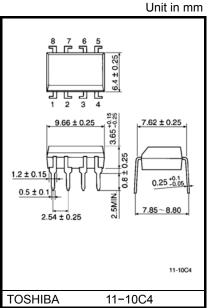
Switching Power Supply

**Transistor Inverter** 

The TOSHIBA TLP2530 and TLP2531 dual photocouplers consist of a pair of GaAlAs light emitting diode and integrated photodetector. This unit is 8–lead DIP.

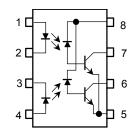
Separate connection for the photodiode bias and output transistor collectors improve the speed up to a hundred times that of a conventional phototransistor coupler by reducing the base-collector capacitance.

- TTL compatible
- Switching speed:  $t_{pHL}$ =0.3 $\mu s$ ,  $t_{pLH}$ =0.3 $\mu s$ (typ.) (@R<sub>L</sub>=1.9 $k\Omega$ )
- Guaranteed performance over temp: 0~70°C
- Isolation voltage: 2500 Vrms(min.)
- UL recognized: UL1577, file no. E67349



Weight: 0.54 g (typ.)

# Pin Configuration (top view)



1. : Anode.1

2.: Cathode.1

3. : Cathode.2

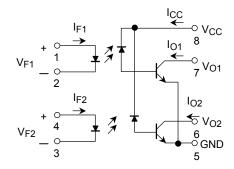
4. : Anode.2 5. : Gnd

6. : V<sub>O2</sub>(output 2)

7. : V<sub>O1</sub>(output 1)

8. : V<sub>CC</sub>

#### **Schematic**





#### **Absolute Maximum Ratings**

	Characteristic	Symbol	Rating	Unit	
LED	Forward current(each channel)	(Note 1)	IF	25	mA
	Pulse forward current (Each Channel)	(Note 2)	I <sub>FP</sub>	50	mA
	Total pulse forward current (each channel)	(Note 3)	I <sub>FPT</sub>	1	Α
	Reverse voltage(each channel)		V <sub>R</sub>	5	V
	Diode power dissipation (each channel)	(Note 4)	PD	45	mW
	Output current(each channel)		IO	8	mA
Detector	Peak output current (each channel)		I <sub>OP</sub>	16	mA
	Supply voltage		V <sub>CC</sub>	-0.5~15	V
	Output voltage(each channel)		Vo	-0.5~15	V
	Output power dissipation (each channel)	(Note 5)	PO	35	mW
Оре	erating temperature range	T <sub>opr</sub>	-55~100	°C	
Sto	rage temperature range	T <sub>stg</sub>	-55~125	°C	
Lea	d solder temperature(10s)**	T <sub>sol</sub>	260	°C	
	ation voltage , 1min., R.H.≤ 60%)	BVS	2500	Vrms	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Derate 0.8mA above 70°C.

(Note 2) 50% duty cycle, 1ms pulse width. Derate 1.6mA / °C above 70°C.

(Note 3) Pulse width 1µs, 300pps.

(Note 4) Derate 0.9mW / °C above 70°C.

(Note 5) Derate 1mW / °C above 70°C.

### **Recommended Operating Conditions**

Characteristic	Symbol	Min.	Тур.	Max.	Unit
Supply voltage	V <sub>CC</sub>	0	_	12	V
Forward current, each channel	lF	_	16	25	mA
Operating temperature	T <sub>opr</sub>	-25	_	85	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

<sup>\*\*2</sup>mm below seating plane.



# Electrical Characteristics Over Recommended Temperature (Ta = $0^{\circ}$ C~70°C, unless otherwise noted)

Characteristic		Symbol	Test Condition	Test Condition		Typ.**	Max.	Unit
	TLP2530	CTR	I <sub>F</sub> = 16mA, V <sub>O</sub> = 0.4V V <sub>CC</sub> = 4.5V, Ta = 25°C		7	30	_	. %
Current transfer ratio	TLP2531	Onc		(Note 6)	19	30	_	70
(each channel)	TLP2530	CTR	I <sub>F</sub> = 16mA, V <sub>O</sub> = 0.5V	(Note 6)	5			%
	TLP2531	CIK	$V_{CC} = 4.5V$ (		15	_	_	/0
Logic low output voltage	TLP2530	V <sub>OL</sub>	I <sub>F</sub> = 16mA, I <sub>O</sub> = 1.1mA V <sub>CC</sub> = 4.5V		_	0.1	0.4	V
(each channel)	TLP2531	VOL	I <sub>F</sub> = 16mA, I <sub>O</sub> = 2.4mA V <sub>CC</sub> = 4.5V		_	0.1	0.4	V
Logic high output current (each channel)		I <sub>OH</sub>	$I_F = 0$ mA, $V_O = V_{CC} = 5.5$ V Ta = 25°C			3	500	nA
			$I_F = 0 \text{mA}, V_O = V_{CC} = 15 \text{V}$		_		50	μA
Logic low supply currer	nt	ICCL	$I_{F1} = I_{F2} = 16mA$ $V_{O1} = V_{O2} = Open$ $V_{CC} = 15V$	_	160		μА	
Logic high supply curre	ent	Іссн	I <sub>F1</sub> = I <sub>F2</sub> = 0mA V <sub>O1</sub> = V <sub>O2</sub> = Open V <sub>CC</sub> = 15V		_	0.05	4	μA
Input forward voltage (each channel)		V <sub>F</sub>	I <sub>F</sub> = 16mA, Ta = 25°C		_	1.65	1.7	V
Temperature coefficent of forward voltage(each channel)		ΔV <sub>F</sub> / ΔTa	I <sub>F</sub> = 16mA		_	-2		mV/°C
Input reverse breakdown voltage(each channel)		BV <sub>R</sub>	IR = 10μA, Ta = 25°C		5	_		V
Input capacitance (each channel)		C <sub>IN</sub>	f = 1MHz, V <sub>F</sub> = 0		_	60	_	pF
Input-output insulation leakage current		I <sub>I-O</sub>	Relative humidity = 45% t = 5s, $V_{I-O}$ = 3000 $V_{dc}$ Ta = 25°C (	(Note 7)	_		1.0	μΑ
Resistance (input-output)		R <sub>I-O</sub>	$V_{I-O} = 500V_{dc}$ (	(Note 7)	_	10 <sup>12</sup>	_	Ω
Capacitance (input-ou	tput)	C <sub>I-O</sub>	f = 1MHz (	(Note 7)	_	0.6	_	pF
Input-input leakage current		I <sub>I—I</sub>	Relative humidity = 45% t = 5s, $V_{I-I}$ = 500V (Note 8)		_	0.005	_	μА
Resistance (input-input)		$R_{I-I}$	$V_{I-I} = 500V_{dc}$ (	(Note 8)	_	10 <sup>11</sup>	_	Ω
Capacitance (input-iut	Capacitance (input-iutput)		f = 1MHz (	(Note 8)	_	0.25	_	pF

<sup>\*\*</sup>All typicals at Ta = 25°C.

## Switching Characteristics (unless otherwise specified, Ta = 25°C, V<sub>CC</sub> = 5V, I<sub>F</sub> = 16mA)

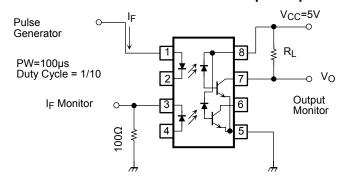
Characteristic		Symbol	Test Cir– cuit	Test Condition	Min.	Тур.	Max.	Unit	
Propagation delay time to logic low	TLP2530	<sup>t</sup> pHL	1	$R_L = 4.1 k\Omega$		0.3	1.5	μs	
at output (each channel)	TLP2531			R <sub>L</sub> = 1.9kΩ	_	0.2	0.8	μο	
Propagation delay time to logic	TLP2530		1	R <sub>L</sub> = 4.1kΩ	_	0.5	1.5	- μs	
high at output (each channel)	TLP2531	<sup>t</sup> pLH		R <sub>L</sub> = 1.9kΩ	_	0.3	0.8		
Common mode transient immunity at logic	TLP2530	СМН	2	$I_F = 0$ mA, $V_{CM} = 400V_{p-p}$ R <sub>L</sub> = 4.1k $\Omega$	_	1500	_	- V / μs	
high level output (each channel, Note 9)	TLP2531			$I_F = 0$ mA, $V_{CM} = 400V_{p-p}$ R <sub>L</sub> = 1.9k $\Omega$	_	1500	_		
Common mode transient immunity at logic	TLP2530		2	$V_{CM} = 400V_{p-p}$ R <sub>L</sub> = 4.1k $\Omega$ , I <sub>F</sub> = 16mA	_	-1500	_	V / µs	
low level output (each channel, Note 9)	TLP2531	CML		$V_{CM} = 400_{p-p}$ R <sub>L</sub> = 1.9k $\Omega$ , I <sub>F</sub> = 16mA	-	-1500	_		
Bandwidth (each char	BW	3	R <sub>L</sub> = 100Ω	_	2	_	$MH_Z$		

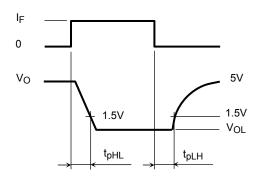
- (Note 6) DC current transfer ratio is defined as the ratio of output collector current, I<sub>O</sub>, to the forward LED input current, I<sub>F</sub>, times 100%.
- (Note 7) Device considered a two–terminal device: Pins 1, 2, 3 and 4 shorted together and pins 5, 6, 7, and 8 shorted together.
- (Note 8) Measured between pins 1 and 2 shorted together, and pins 3 and 4 shorted together.
- (Note 9) Common mode transient immunity in logic high level is the maximum tolerable (positive) dVcm / dt on the leading egde of the common mode pulse, Vcm, to assure that the output will remain in a logic high state(i.e.,  $V_O > 2.0V$ ).

Common mode transient immunity in logic low Level is the maximum tolerable (negative) dVcm / dt on the trailing edge of the common mode pulse signal, Vcm, to assure that the output will remain in logic low state(i.e.,  $V_O > 0.8V$ ).

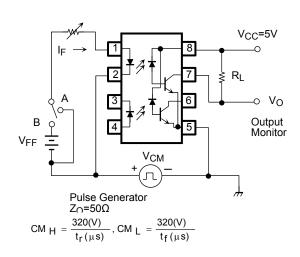
(Note 10) The frequency at which the ac output voltage is 3dB below the low frequency asymptote.

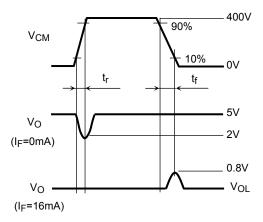
# Test Circuit 1: Switching Time, tpHL, tpLH



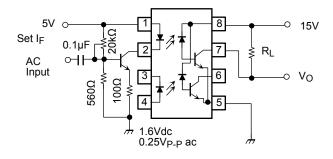


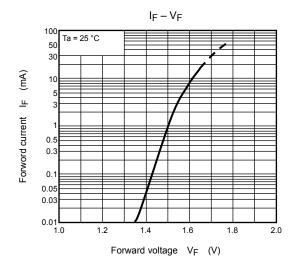
# **Test Circuit 2: Transient Immunity And Typical Waveform**

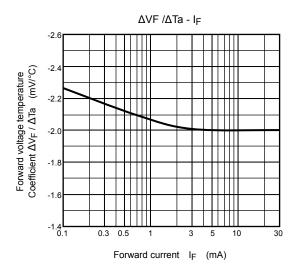


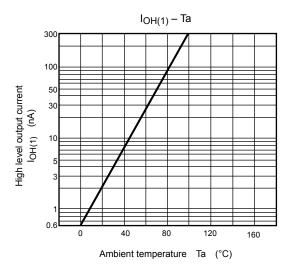


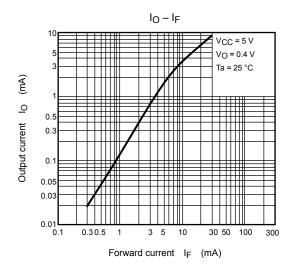
# **Test Circuit 3: Frequency Response**

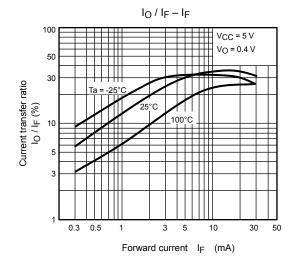


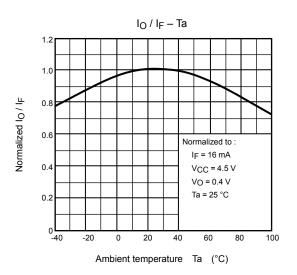


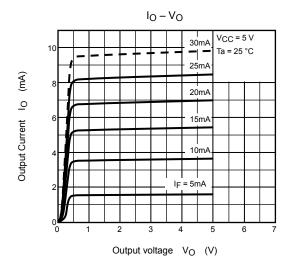


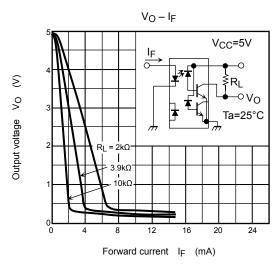


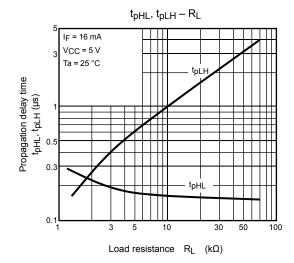












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